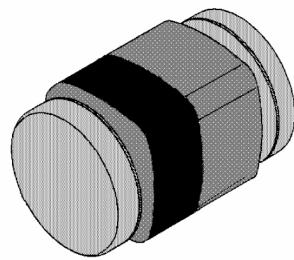


SILICON EPITAXIAL PLANAR DIODE

LS-31

**Features**

- Saving space
- Hermetic sealed parts
- Fits onto SOD 323 / SOT 23 footprints
- Electrical data identical with the device 1N4148
- Micro Melf package

Applications

Extreme fast switches

Absolute Maximum Ratings ($T_j = 25^\circ\text{C}$)

Parameter	Test	Symbol	Value	Unit
Repetitive Peak Reverse Voltage	-	V_{RRM}	100	V
Reverse Voltage	-	V_R	75	V
Peak Forward Surge Current	$t_p = 1 \mu\text{s}$	I_{FSM}	2	A
Repetitive Peak Forward Current	-	I_{FRM}	450	mA
Forward Current	-	I_F	200	mA
Average Forward Current	$V_R = 0$	I_{FAV}	150	mA
Power Dissipation	-	P_{tot}	500	mW
Junction Temperature	-	T_j	175	$^\circ\text{C}$
Storage Temperature Range	-	T_s	-65 ... +175	$^\circ\text{C}$

Maximum Thermal Resistance ($T_j = 25^\circ\text{C}$)

Parameter	Test Conditions	Symbol	Value	Unit
Junction ambient	mounted on epoxy-glass hard tissue, 35 μm copper clad, 0.9 mm^2 copper area per electrode	R_{thJA}	500	K/W

Characteristics at $T_j = 25^\circ\text{C}$

Parameter	Test Conditions	Symbol	Min	Typ	Max	Unit
Forward Voltage	$I_F = 50\text{mA}$	V_F	-	0.86	1	V
Reverse Current	$V_R = 20\text{V}$	I_R	-	-	25	nA
	$V_R = 20\text{V}, T_j = 150^\circ\text{C}$	I_R	-	-	50	μA
	$V_R = 75\text{V}$	I_R	-	-	5	μA
Breakdown Voltage	$I_R = 100\text{nA}, tp/T = 0.01,$ $T_p = 0.3\text{ms}$	$V_{(\text{BR})}$	100	-	-	V
Diode Capacitance	$V_R = 0, f = 1\text{MHz}, V_{HF} = 50\text{mV}$	C_D	-	-	4	pF
Rectification Efficiency	$V_{HF} = 2\text{V}, f = 100\text{MHz}$	η_r	45	-	-	%
Reverse Recovery Time	$I_F = I_R = 10\text{mA}, I_r \text{ A}$	t_{rr}	-	-	8	ns
	$I_F = 10\text{mA}, V_R = 6\text{V}, i_R = 0.1 \times I_R,$ $R_L = 100\Omega$	t_{rr}	-	-	4	ns

Dimensions in mm

